Notice of References Cited Application/Control No. 10/801,154 Examiner XIAO M. WU Applicant(s)/Patent Under Reexamination AHN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,342,934	01-2002	Kameyama et al.	349/98
*	В	US-6,392,727	05-2002	Larson et al.	349/96
*	С	US-6,549,195	04-2003	Hikida et al.	345/173
*	D	US-2001/0000961	05-2001	Hikida et al.	345/173
*	E	US-2001/0031835	10-2001	Ohrui et al.	525/329.7
*	F	US-2002/0033919	03-2002	Sanelle et al.	349/122
*	G	US-2003/0038916	02-2003	Nakano et al.	349/158
*	Н	US-2003/0081151	05-2003	Tsuchihashi et al.	349/61
	1	US-			
	J	US-			
	К	US-			
	L	US-	7		
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					4
	σ					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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